Special Issue on Metrology

Call for Papers

Metrology is the science of measurement. Metrology is divided into three basic overlapping activities. The first is the definition of units of measurement; the second is the realization of these units of measurement in practice, and the final traceability, which links actual measurements to reference standards. These overlapping activities are used in varying degrees by the three basic sub-fields of metrology. Metrology has broad implications for the economy, energy, environment, health, manufacturing, industry and consumer confidence.

In this special issue, we intend to invite front-line researchers and authors to submit original researches and review articles on exploring metrology. Potential topics include, but are not limited to:

- Applied metrology
- Legal metrology
- Speckle metrology
- Precision metrology
- Dimensional metrology
- Optical metrology
- Quantum metrology

Authors should read over the journal’s For Authors carefully before submission. Prospective authors should submit an electronic copy of their complete manuscript through the journal’s Paper Submission System.

Please kindly notice that the “Special Issue” under your manuscript title is supposed to be specified and the research field “Special Issue – Metrology” should be chosen during your submission.

According to the following timetable:

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<th>Submission Deadline</th>
<th>August 1st, 2018</th>
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<td>Publication Date</td>
<td>October 2018</td>
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Guest Editor:

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